

# Supporting Information

## Highly thermostable fluoride nanocrystal-in-glass composite (NGC) for mid-infrared emission

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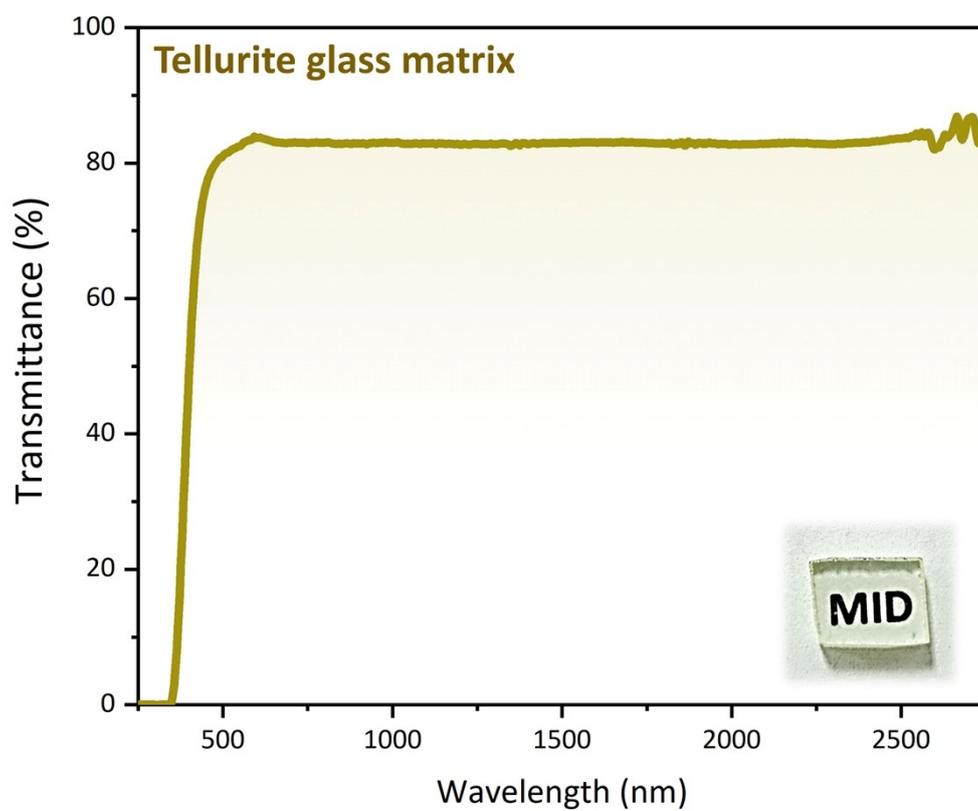
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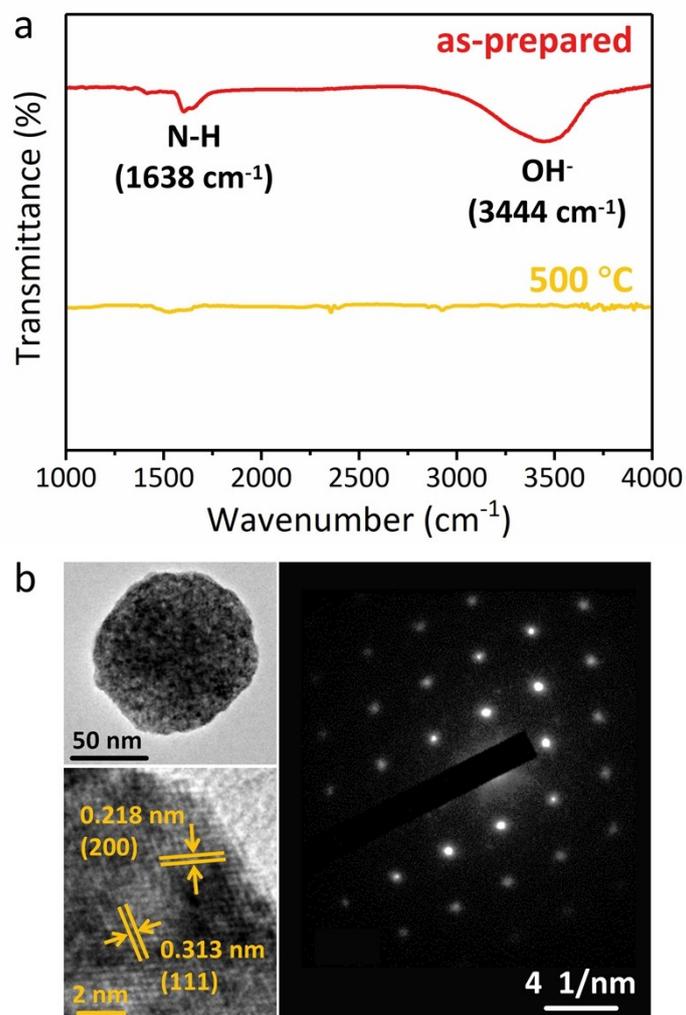
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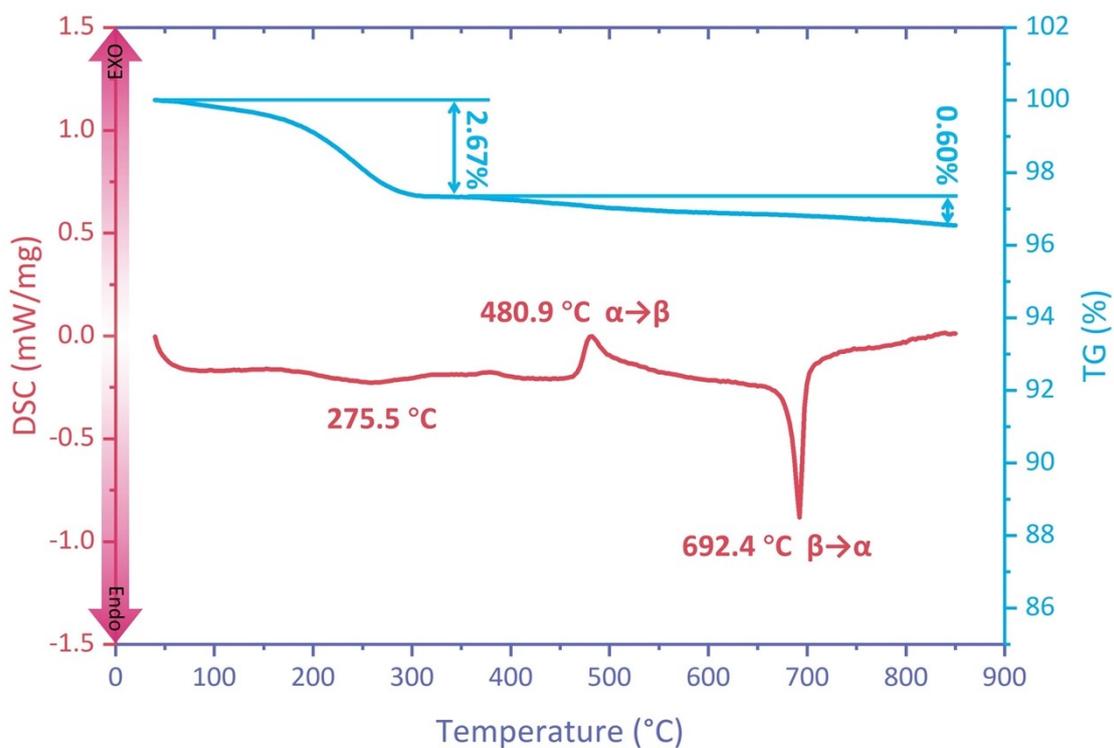


**Fig. S1** Ultraviolet-visible-infrared transmission spectrum of the as-prepared tellurite glass matrix.

The inset is the photograph of the as-prepared tellurite glass matrix.

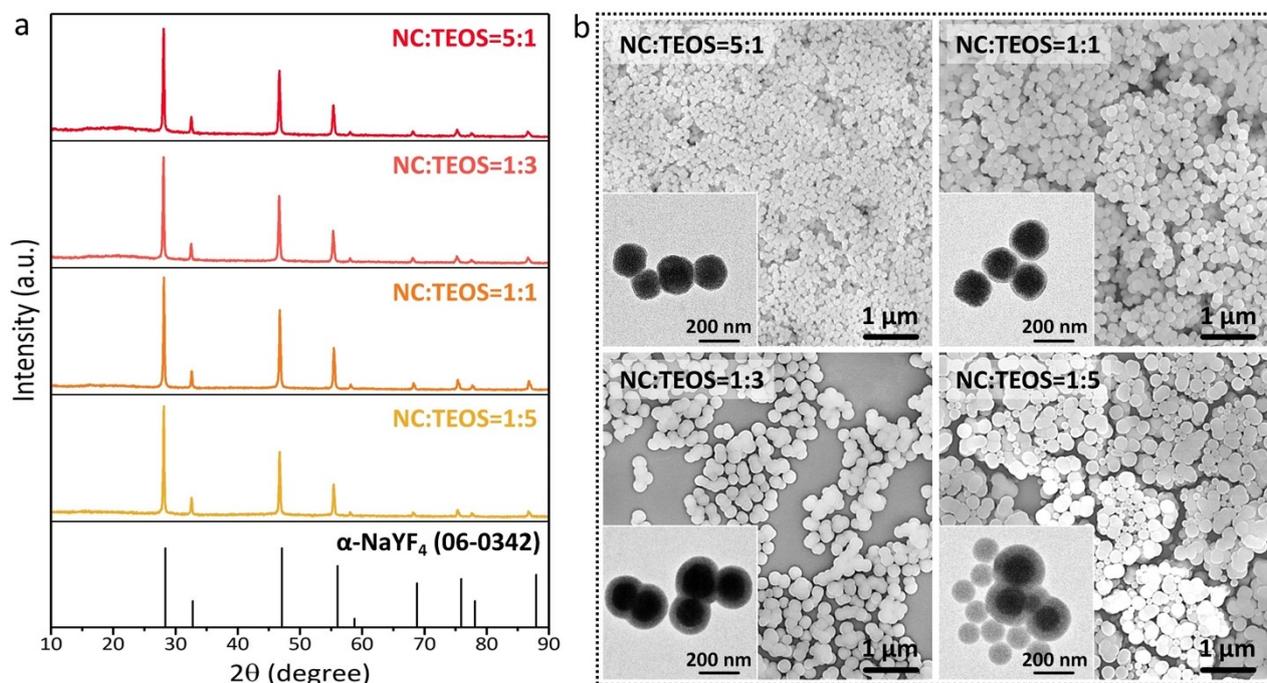


**Fig. S2** (a) Fourier transform-infrared spectroscopy spectra of the as-prepared NaYF<sub>4</sub>:Er<sup>3+</sup> nanocrystals (NCs) and their thermal annealing at 500 °C for 2 h. (b) Transmission electron microscopy (TEM) image (top left), high-resolution TEM image (bottom left), and selected area electron diffraction pattern (right) of a single as-prepared NaYF<sub>4</sub>:Er<sup>3+</sup> NC.

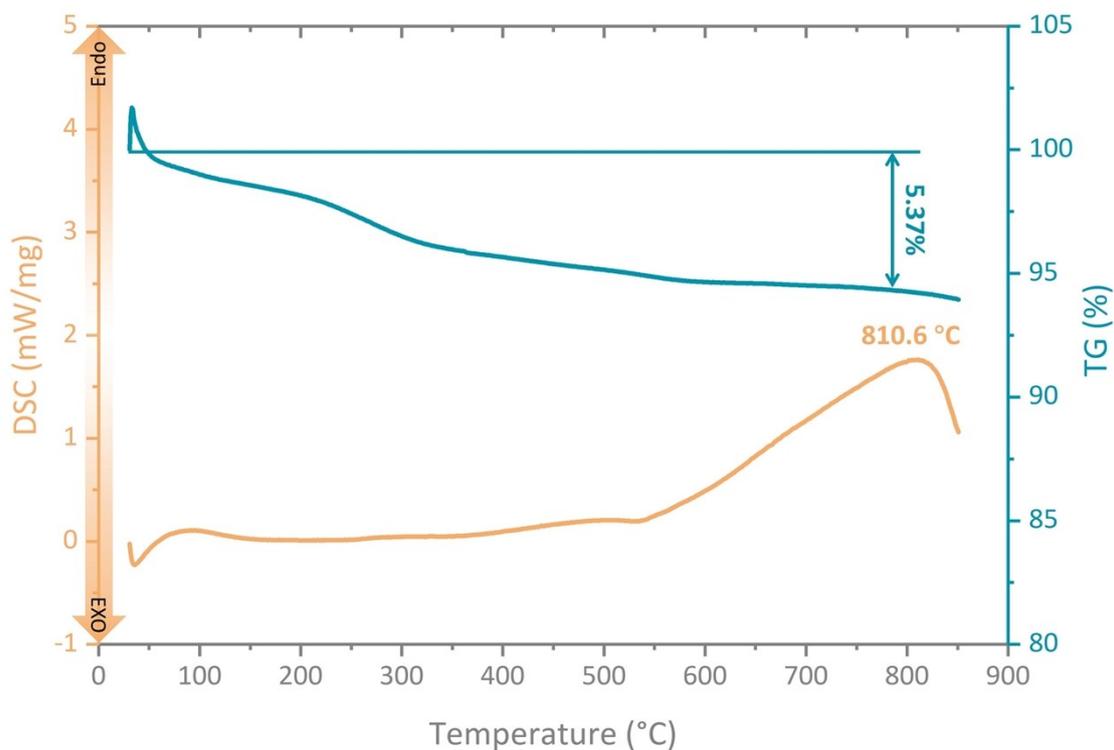


**Fig. S3** Thermogravimetry-differential scanning calorimetry (TG-DSC) curves of the as-prepared NaYF<sub>4</sub>:Er<sup>3+</sup> NCs in air atmosphere with a heating rate of 10 °C/min.

DSC curve exhibits two endothermic peaks and one exothermic peak. The first endothermic peak at 270.5 °C is due to the dehydration and combustion of the surface organic ligands, which results in a weight loss of 2.67%. The exothermic peak at 480.9 °C and the endothermic peak at 692.4 °C correspond to the phase transition between cubic ( $\alpha$ ) and hexagonal ( $\beta$ ) NaYF<sub>4</sub>. The vaporization of some residual organic ligands during this process leads to a weight loss of 0.6%.

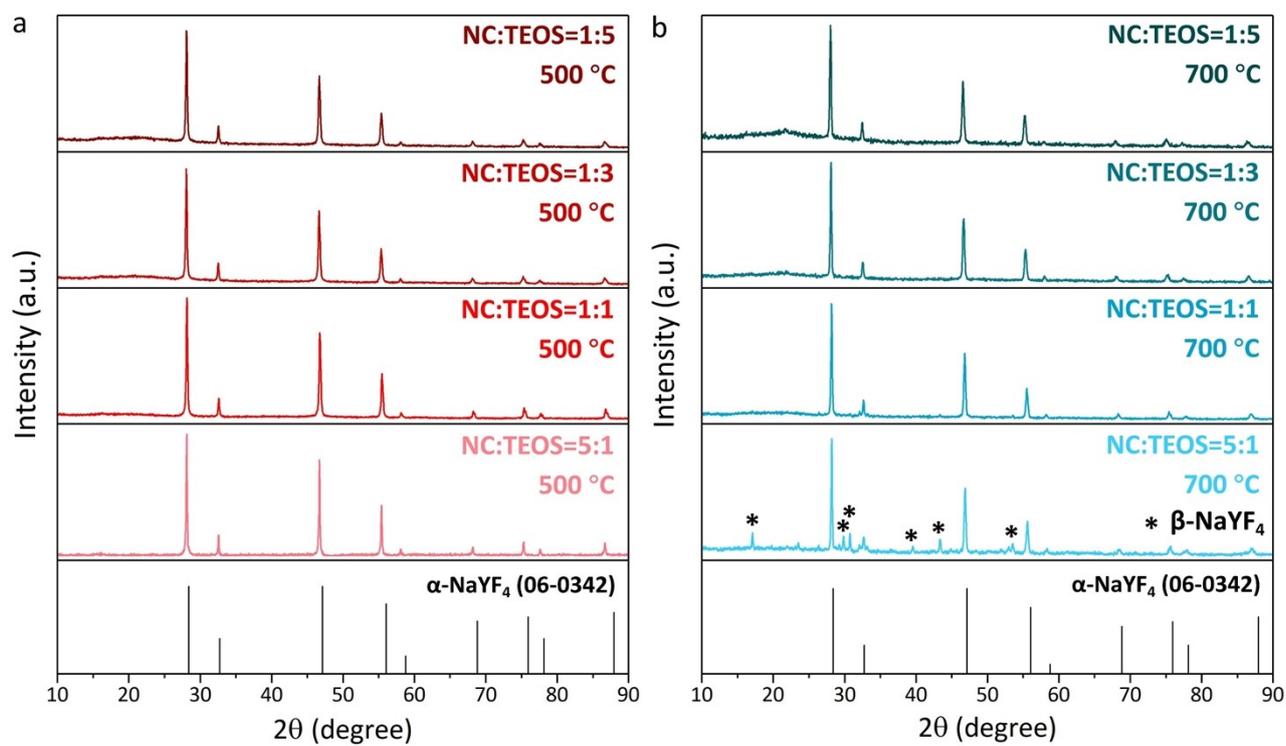


**Fig. S4** (a) X-ray diffraction (XRD) patterns and (b) scanning electron microscopy (SEM) images of NaYF<sub>4</sub>:Er<sup>3+</sup>@SiO<sub>2</sub> NCs prepared at different mass ratios between NaYF<sub>4</sub>:Er<sup>3+</sup> NCs and tetraethyl orthosilicate (TEOS). Insets in (b) are corresponding TEM images.

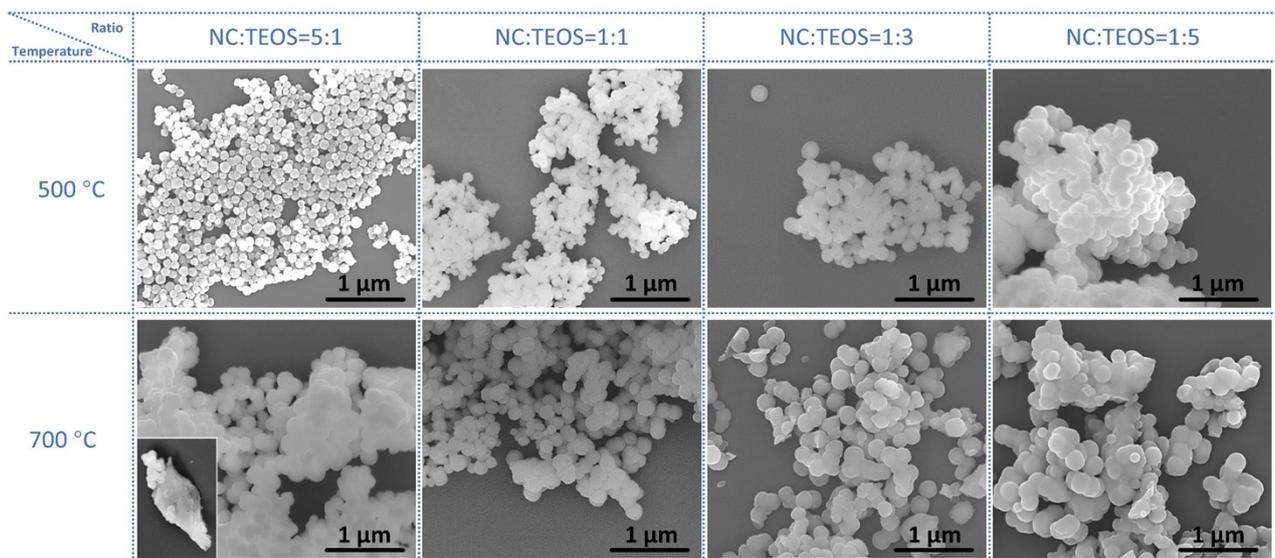


**Fig. S5** (a) TG-DSC curves of the as-prepared  $\text{NaYF}_4:\text{Er}^{3+}@\text{SiO}_2$  NCs in air atmosphere with a heating rate of  $10\text{ }^\circ\text{C}/\text{min}$ .

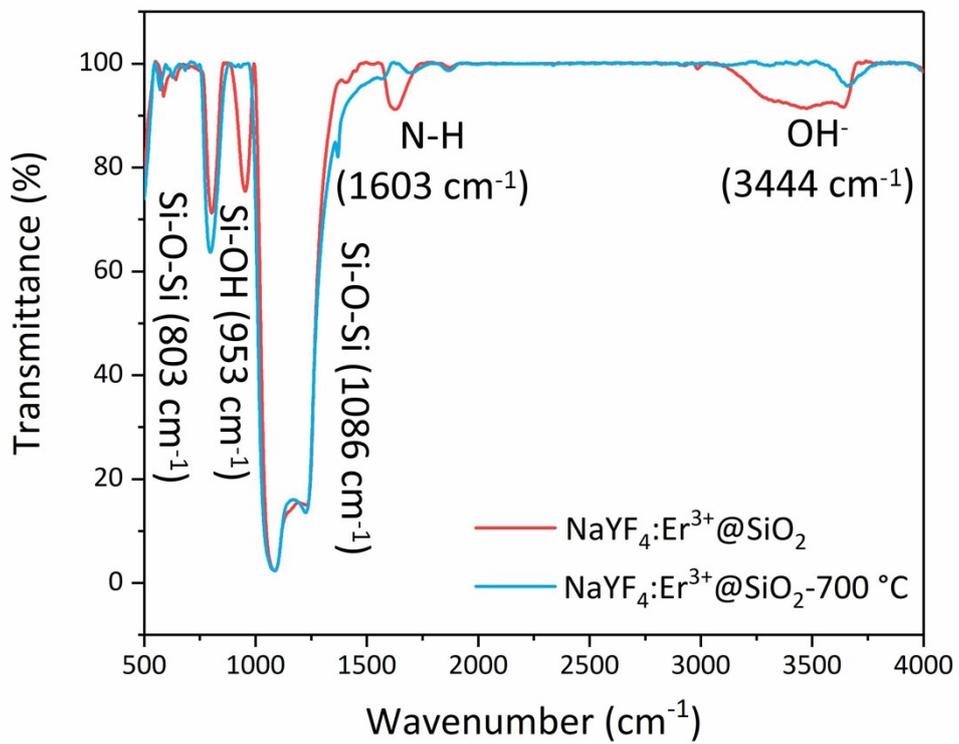
The DSC curve shows there are no endothermic or exothermic peaks below  $800\text{ }^\circ\text{C}$ , indicating as-prepared  $\text{NaYF}_4:\text{Er}^{3+}@\text{SiO}_2$  NCs did not go through phase transition processes. But during this temperature range, there is a 5.37% weight loss. This can be attributed to the dehydration and combustion of surface organic ligands. Due to the protection of the  $\text{SiO}_2$  shell, this is a very slow process, so that no endothermic peak was detected. When the temperature is above  $800\text{ }^\circ\text{C}$ , there is an endothermic process. According to the XRD pattern of  $\alpha\text{-NaYF}_4:\text{Er}^{3+}@\text{SiO}_2$  NCs annealed at  $800\text{ }^\circ\text{C}$  (**Fig. S9**), this endothermic process is a complex process, including the phase transformation between  $\alpha$ - and  $\beta$ - $\text{NaYF}_4$  as well as the reaction between  $\text{NaYF}_4$  and  $\text{SiO}_2$ .



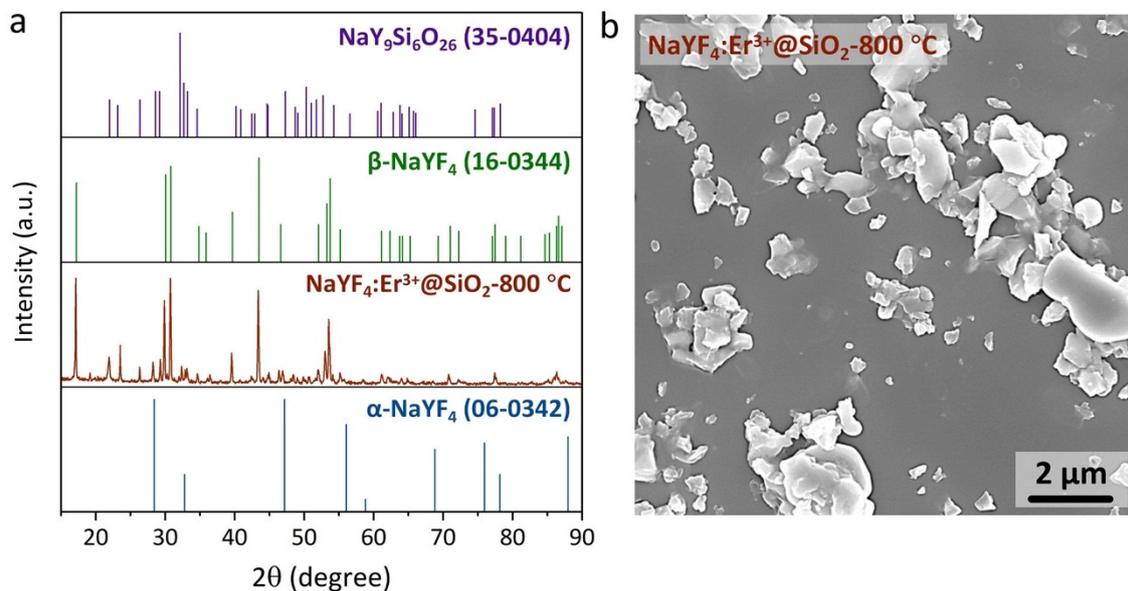
**Fig. S6** XRD patterns of NaYF<sub>4</sub>:Er<sup>3+</sup>@SiO<sub>2</sub> NCs prepared at different mass ratios between NaYF<sub>4</sub>:Er<sup>3+</sup> NCs and TEOS annealed at different temperatures for 2 h: (a) 500 °C, (b) 700 °C.



**Fig. S7** SEM images of  $\text{NaYF}_4:\text{Er}^{3+}@\text{SiO}_2$  NCs prepared at different mass ratios between  $\text{NaYF}_4:\text{Er}^{3+}$  NCs and TEOS annealed at 500 °C and 700 °C for 2 h, respectively.

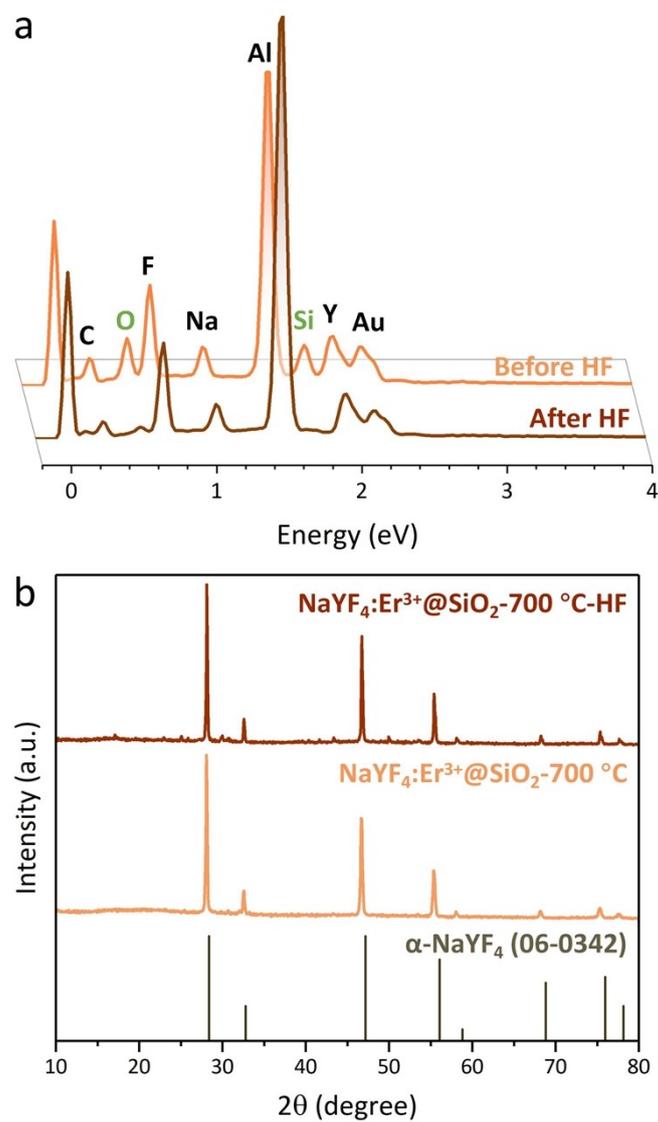


**Fig. S8** FTIR spectra of the as-prepared NaYF<sub>4</sub>:Er<sup>3+</sup>@SiO<sub>2</sub> NCs and their thermal annealing at 700 °C for 2 h.



**Fig. S9** (a) XRD patterns and (b) SEM image of the as-prepared  $\text{NaYF}_4:\text{Er}^{3+}@\text{SiO}_2$  NCs annealed at 800 °C for 2 h.

As shown in this Figure, when increasing the annealing temperature to 800 °C, multiple crystalline phases appear in the samples, including  $\alpha\text{-NaYF}_4$ ,  $\beta\text{-NaYF}_4$ , and silicon oxides. This indicates that at higher temperature ( $\geq 800$  °C),  $\text{NaYF}_4$  would react with  $\text{SiO}_2$  shell, and without protection of  $\text{SiO}_2$  shell, most unreacted  $\alpha\text{-NaYF}_4$  would transform into  $\beta\text{-NaYF}_4$ . This series of transitions also led to a serious morphological collapse. Accordingly, the highest thermal stability temperature of the as-prepared  $\text{NaYF}_4:\text{Er}^{3+}@\text{SiO}_2$  NCs is 700 °C.



**Fig. S10** (a) Compositional analysis and (b) XRD patterns of NaYF<sub>4</sub>:Er<sup>3+</sup>@SiO<sub>2</sub> NCs annealed at 700 °C for 2 h before and after hydrofluoric acid (HF) treatment.